查询"2SK39470<mark>供和的</mark> Field Effect Transistor Silicon N-Channel MOS Type (π-MOSVI)

2SK3947

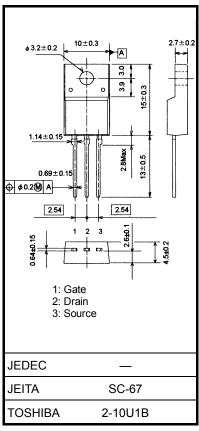
Switching Regulator Applications

Unit: mm

- Low drain-source ON-resistance: $R_{DS (ON)} = 1.1 \Omega (typ.)$
- High forward transfer admittance: $|Y_{fS}| = 5.0S$ (typ.)
- Low leakage current: $I_{DSS} = 100 \mu A (V_{DS} = 600 V)$
- Enhancement mode: $V_{th} = 2.0 \sim 4.0 \text{ V} (V_{DS} = 10 \text{ V}, I_D = 1 \text{ mA})$

Absolute Maximum Ratings (Ta = 25°C)

Characte	ristic	Symbol	Rating	Unit
Drain-source voltage		V_{DSS}	600	V
Drain-gate voltage ($R_{GS} = 20 \text{ k}\Omega$)		V_{DGR}	600	V
Gate-source voltage		V _{GSS}	±30	V
Drain current	DC (Note 1)	I _D	6	
	Pulse (t = 1 ms) (Note 1)	I _{DP}	24	Α
Drain power dissipati	on (Tc = 25°C)	PD	40	W
Single-pulse avalanche energy (Note 2)		E _{AS}	345	mJ
Avalanche current		I _{AR}	6	Α
Repetitive avalanche	energy (Note 3)	E _{AR}	4	mJ
Channel temperature		T _{ch}	150	°C
Storage temperature range		T _{stg}	-55~150	°C



Weight: 1.7 g (typ.)

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Thermal Characteristics

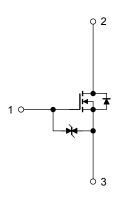
Characteristic	Symbol	Max	Unit
Thermal resistance, channel to case	R _{th (ch-c)}	3.125	°C/W
Thermal resistance, channel to ambient	R _{th (ch-a)}	62.5	°C/W



Note 2:
$$V_{DD} = 90 \text{ V}$$
, $T_{ch} = 25^{\circ}\text{C}$ (initial), $L = 16.8 \text{ mH}$, $I_{AR} = 6 \text{ A}$, $R_G = 25 \Omega$

Note 3: Repetitive rating: Pulse width limited by maximum channel temperature

This transistor is an electrostatic-sensitive device. Handle with care.



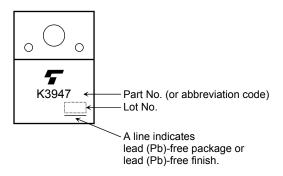
Energy istics (Ta = 25°C)

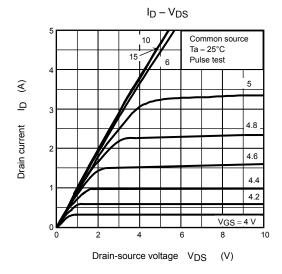
Characteristic		Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cui	rrent	I _{GSS}	$V_{GS} = \pm 25 \text{ V}, V_{DS} = 0 \text{ V}$	_	— <u>±10</u>		μΑ
Gate-source breakdown voltage		V (BR) GSS	$I_G = \pm 10 \ \mu A, \ V_{GS} = 0 \ V$	±30	_	_	V
Drain cutoff current		I _{DSS}	V _{DS} = 600 V, V _{GS} = 0 V	_	_	100	μΑ
Drain-source breakdown voltage		V (BR) DSS	$I_D = 10 \text{ mA}, V_{GS} = 0 \text{ V}$	600	_	_	V
Gate threshold voltage		V _{th}	V _{DS} = 10 V, I _D = 1 mA	2.0	_	4.0	V
Drain-source ON	-resistance	R _{DS} (ON)	V _{GS} = 10 V, I _D = 3 A	_	1.1	1.4	Ω
Forward transfer	nsfer admittance $ Y_{fs} $ $V_{DS} = 10 \text{ V}, I_D = 3 \text{ A}$		1.2	5.0	_	S	
Input capacitance	е	C _{iss}		_	1050		
Reverse transfer capacitance		C _{rss}	V _{DS} = 25 V, V _{GS} = 0 V, f = 1 MHz	_	10		pF
Output capacitance		C _{oss}		_	110	_	
Switching time	Rise time	t _r	$\begin{array}{c c} 10 \text{ V} \\ \text{VGS} \\ 0 \text{ V} \end{array}$ $\begin{array}{c c} \text{ID} = 3 \text{ A} \\ \text{VOUT} \end{array}$ $\begin{array}{c c} \text{RL} = \\ 66 \Omega \\ \text{VDD} \approx 200 \text{ V} \end{array}$	_	20	_	
	Turn-on time	t _{on}			40	_	
	Fall time	t _f			35	_	ns
	Turn-off time	t _{off}	Duty \leq 1%, $t_W = 10 \mu s$	_	130	_	
Total gate charge		Qg		_	28		
Gate-source charge		Q _{gs}	$V_{DD} \simeq 400 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 6 \text{ A}$	_	16	_	nC
Gate-drain charge		Q _{gd}			12	_	

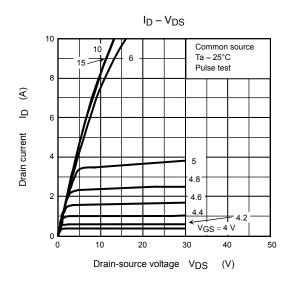
Source-Drain Ratings and Characteristics (Ta = 25°C)

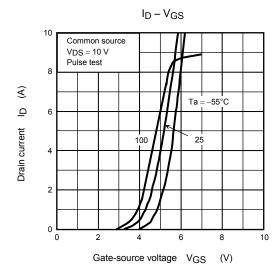
Characteristic		Symbol	Test Condition	Min	Тур.	Max	Unit
Continuous drain reverse current	(Note 1)	I _{DR}	_	_	_	6	Α
Pulse drain reverse current	(Note 1)	I _{DRP}	_	_	_	24	Α
Forward voltage (diode)		V _{DSF}	I _{DR} = 6 A, V _{GS} = 0 V	_	_	-1.7	V
Reverse recovery time		t _{rr}	I _{DR} = 6 A, V _{GS} = 0 V,	_	140	_	ns
Reverse recovery charge		Q _{rr}	dl _{DR} /dt = 100 A/μs	_	0.3	_	μС

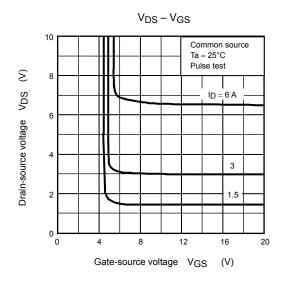
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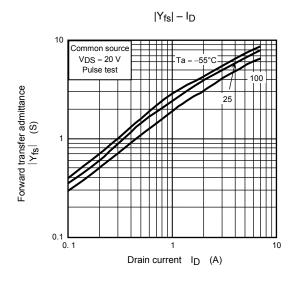


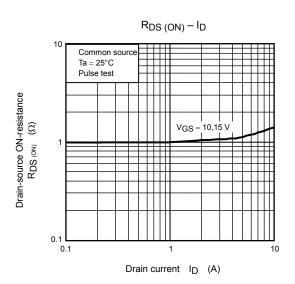


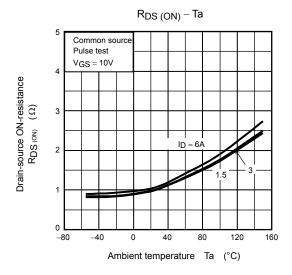


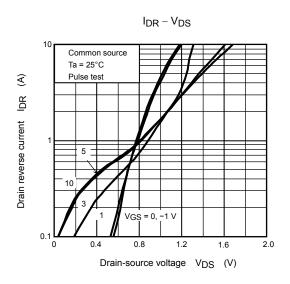


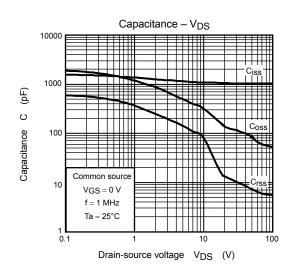


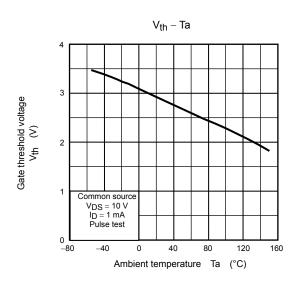


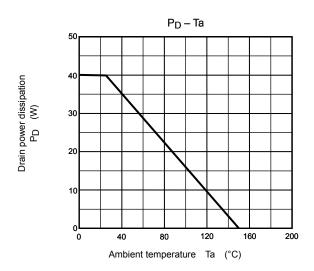


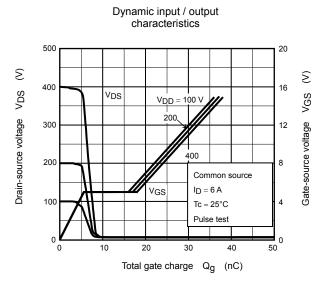


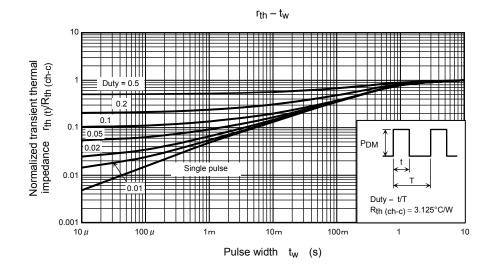


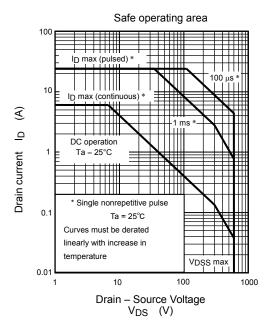


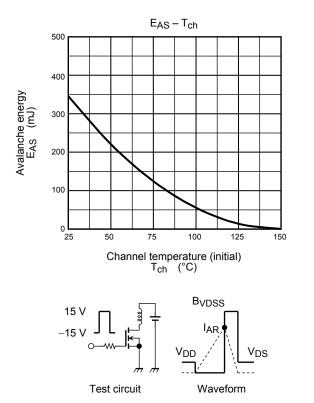












$$R_G = 25 \Omega$$

 $V_{DD} = 90 \text{ V, L} = 16.8 \text{ mH}$ $E_{AS} = \frac{1}{2} \cdot L$

$$EAS = \frac{1}{2} \cdot L \cdot I^2 \cdot \left(\frac{BVDSS}{BVDSS - VDD} \right)$$

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